

MT40018T

N-Channel Enhancement Mode MOSFET

Feature Description

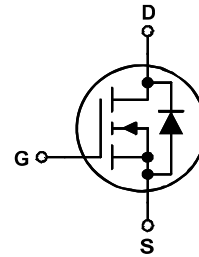
- 40V/240A
 $R_{DS(ON)}=2.0m\Omega(\text{typ.})@V_{GS} = 10V$
 $R_{DS(ON)}=2.4m\Omega(\text{typ.}) @V_{GS} = 4.5V$
- 100% avalanche tested
- Excellent CdV/dt effect decline
- Halogen - Free Device Available



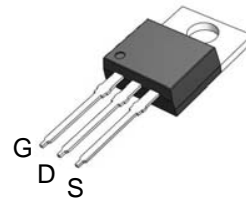
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Simplified Schematic



MARKING DIAGRAM & PIN ASSIGNMENT



TO-220FB-3L

Applications

- High Frequency Switching and Synchronous Rectification
- BLDC

Absolute Maximum Ratings $(T_A = 25^\circ\text{C}$ unless otherwise noted)

Absolute Maximum Ratings $T_A=25^\circ\text{C}$ unless otherwise noted			
Parameter	Symbol	Maximum	Units
Drain-Source Voltage	V_{DS}	40	V
Gate-Source Voltage	V_{GS}	± 20	V
Continuous Drain Current ^G	$T_C=25^\circ\text{C}$	240	A
	$T_C=100^\circ\text{C}$	240	
Pulsed Drain Current ^C	I_{DM}	720	
Continuous Drain Current	$T_A=25^\circ\text{C}$	90	A
	$T_A=70^\circ\text{C}$	80	
Avalanche Current ^C	I_{AS}	96	A
Avalanche energy	$L=0.3mH$ ^C E_{AS}	346	mJ
Power Dissipation ^B	$T_C=25^\circ\text{C}$	125	W
	$T_C=100^\circ\text{C}$	80	
Power Dissipation ^A	$T_A=25^\circ\text{C}$	8.3	W
	$T_A=70^\circ\text{C}$	5.3	
Junction and Storage Temperature Range	T_J, T_{STG}	-55 to 150	$^\circ\text{C}$

Thermal Characteristics					
Parameter		Symbol	Typ	Max	Units
Maximum Junction-to-Ambient ^A	$t \leq 10s$	$R_{\theta JA}$	12	15	$^{\circ}C/W$
Maximum Junction-to-Ambient ^{A,B}	Steady-State		50	60	$^{\circ}C/W$
Maximum Junction-to-Case	Steady-State	$R_{\theta JC}$	0.4	0.48	$^{\circ}C/W$

Electrical Characteristics ($T_J=25^{\circ}C$ unless otherwise noted)

Symbol	Parameter	Conditions	Min	Typ	Max	Units
STATIC PARAMETERS						
BV_{DSS}	Drain-Source Breakdown Voltage	$I_D=250\mu A, V_{GS}=0V$	40			V
I_{DSS}	Zero Gate Voltage Drain Current	$V_{DS}=24V, V_{GS}=0V$ $T_J=55^{\circ}C$			1 5	μA
I_{GSS}	Gate-Body leakage current	$V_{DS}=0V, V_{GS}=\pm 20V$			± 100	nA
$V_{GS(th)}$	Gate Threshold Voltage	$V_{DS}=V_{GS}, I_D=250\mu A$	1.0	1.4	2.0	V
$R_{DS(on)}$	Static Drain-Source On-Resistance	$V_{GS}=10V, I_D=20A$ $T_J=125^{\circ}C$		2.0 2.5	2.2 2.8	m Ω
		$V_{GS}=4.5V, I_D=20A$		2.4	2.6	m Ω
g_{FS}	Forward Transconductance	$V_{DS}=5V, I_D=20A$		100		S
V_{SD}	Diode Forward Voltage	$I_S=1A, V_{GS}=0V$		0.7	1	V
I_S	Maximum Body-Diode Continuous Current ^G				120	A
DYNAMIC PARAMETERS						
C_{iss}	Input Capacitance	$V_{GS}=0V, V_{DS}=15V, f=1MHz$		5300		pF
C_{oss}	Output Capacitance			1500		pF
C_{rss}	Reverse Transfer Capacitance			50		pF
R_g	Gate resistance	$f=1MHz$	0.4	0.9	1.4	Ω
SWITCHING PARAMETERS						
$Q_g(10V)$	Total Gate Charge	$V_{GS}=10V, V_{DS}=15V, I_D=20A$		78	110	nC
Q_{gs}	Gate Source Charge			20		nC
Q_{gd}	Gate Drain Charge			20		nC
Q_{oss}	Output Charge	$V_{GS}=0V, V_{DS}=15V$		92		nC
$t_{D(on)}$	Turn-On DelayTime	$V_{GS}=10V, V_{DS}=15V, R_L=1.5\Omega, R_{GEN}=3\Omega$		23		ns
t_r	Turn-On Rise Time			21		ns
$t_{D(off)}$	Turn-Off DelayTime			40		ns
t_f	Turn-Off Fall Time			13		ns
t_{rr}	Body Diode Reverse Recovery Time	$I_F=20A, di/dt=500A/\mu s$		30		ns
Q_{rr}	Body Diode Reverse Recovery Charge	$I_F=20A, di/dt=500A/\mu s$		135		nC

A. The value of $R_{\theta JA}$ is measured with the device mounted on 1in² FR-4 board with 2oz. Copper, in a still air environment with $T_A=25^{\circ}C$. The Power dissipation P_{DSM} is based on $R_{\theta JA} \leq 10s$ and the maximum allowed junction temperature of $150^{\circ}C$. The value in any given application depends on the user's specific board design.

B. The power dissipation P_D is based on $T_{J(MAX)}=150^{\circ}C$, using junction-to-case thermal resistance, and is more useful in setting the upper dissipation limit for cases where additional heatsinking is used.

C. Single pulse width limited by junction temperature $T_{J(MAX)}=150^{\circ}C$.

D. The $R_{\theta JA}$ is the sum of the thermal impedance from junction to case $R_{\theta JC}$ and case to ambient.

E. The static characteristics in Figures 1 to 6 are obtained using $<300\mu s$ pulses, duty cycle 0.5% max.

F. These curves are based on the junction-to-case thermal impedance which is measured with the device mounted to a large heatsink, assuming a maximum junction temperature of $T_{J(MAX)}=150^{\circ}C$. The SOA curve provides a single pulse rating.

G. The maximum current rating is package limited.

H. These tests are performed with the device mounted on 1 in² FR-4 board with 2oz. Copper, in a still air environment with $T_A=25^{\circ}C$.

TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS

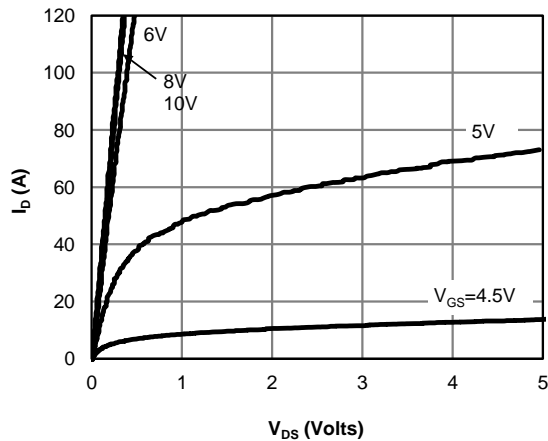


Figure 1: On-Region Characteristics (Note E)

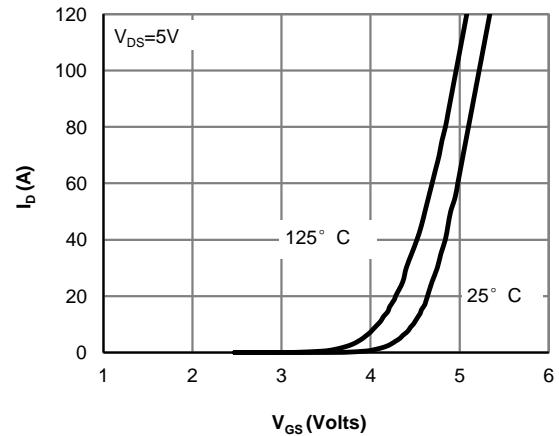


Figure 2: Transfer Characteristics (Note E)

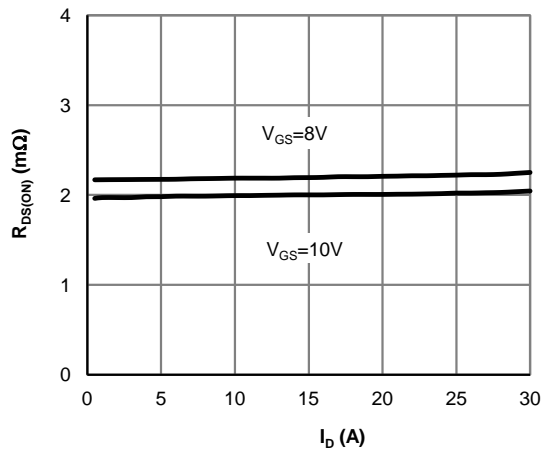


Figure 3: On-Resistance vs. Drain Current and Gate Voltage (Note E)

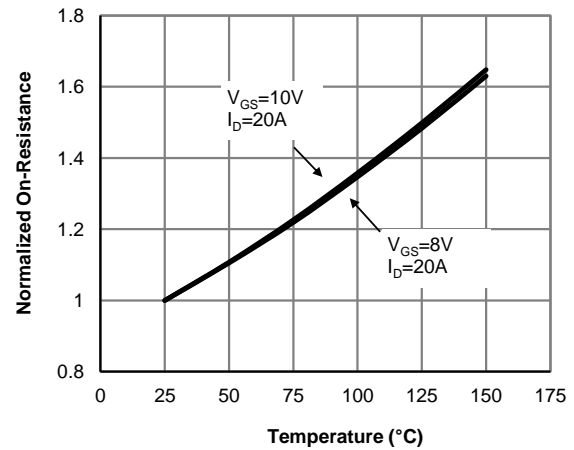


Figure 4: On-Resistance vs. Junction Temperature (Note E)

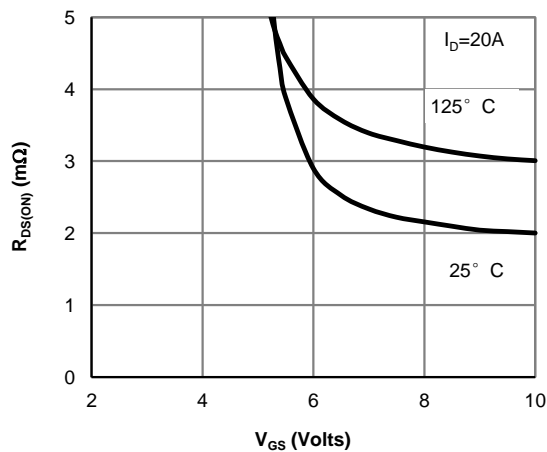


Figure 5: On-Resistance vs. Gate-Source Voltage (Note E)

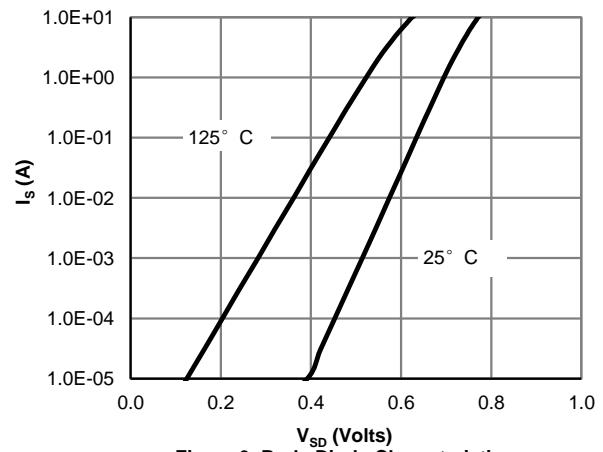


Figure 6: Body-Diode Characteristics (Note E)

TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS

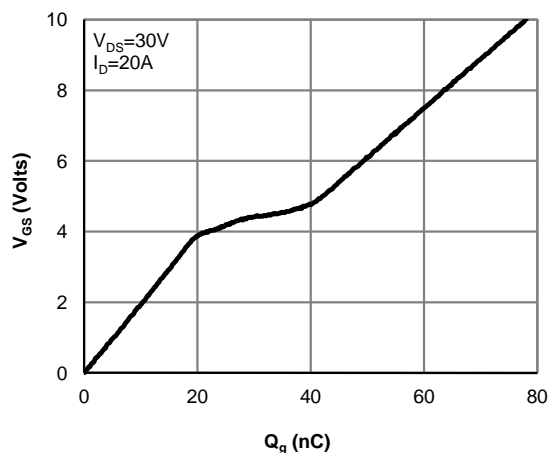


Figure 7: Gate-Charge Characteristics

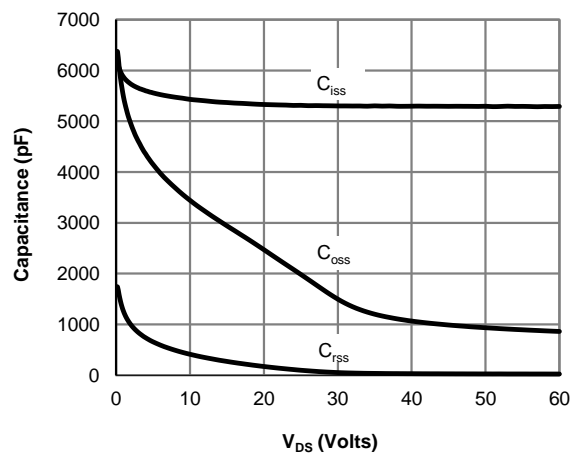


Figure 8: Capacitance Characteristics

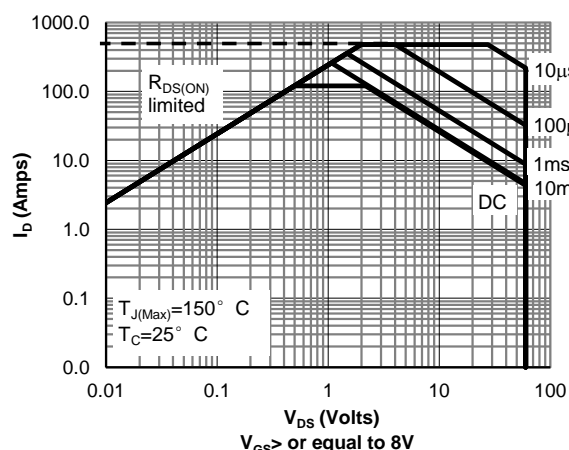


Figure 9: Maximum Forward Biased Safe Operating Area (Note F)

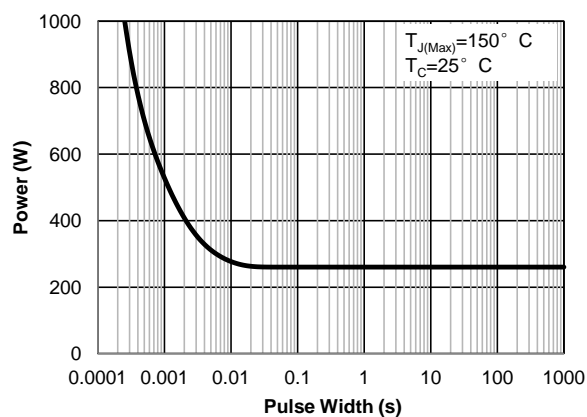


Figure 10: Single Pulse Power Rating Junction-to-Case (Note F)

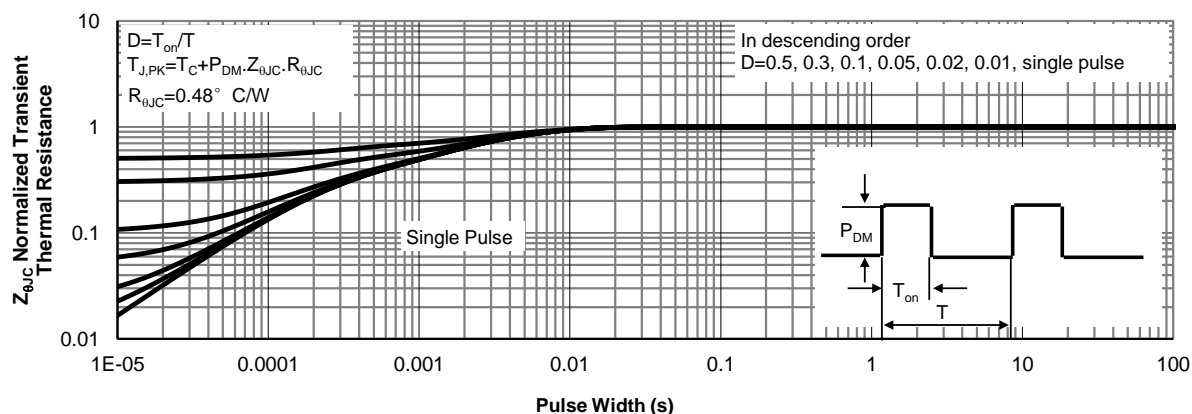


Figure 11: Normalized Maximum Transient Thermal Impedance (Note F)

TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS

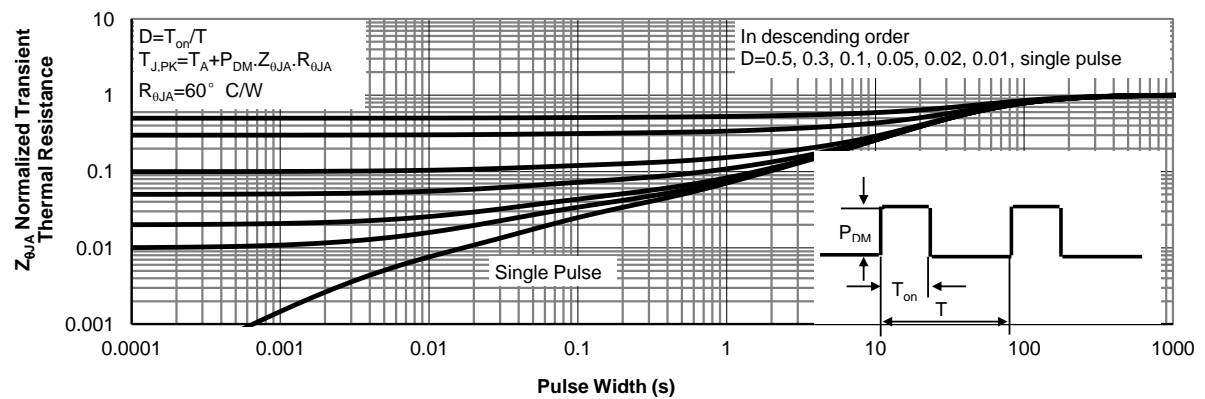
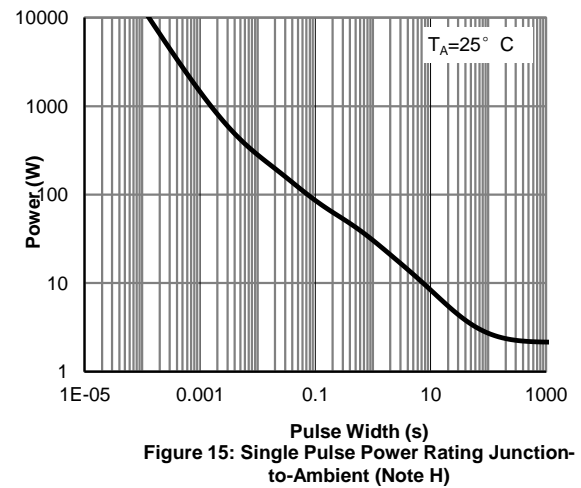
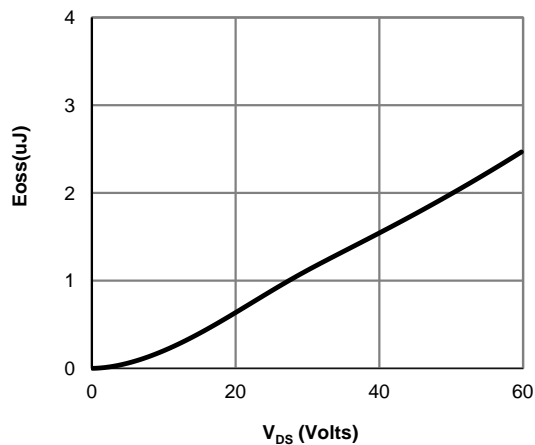
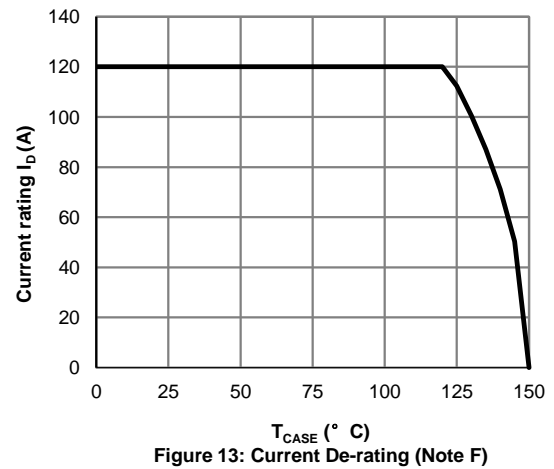
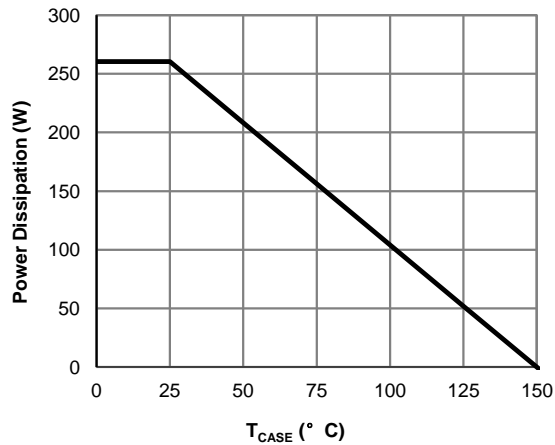


Figure A: Gate Charge Test Circuit & Waveforms

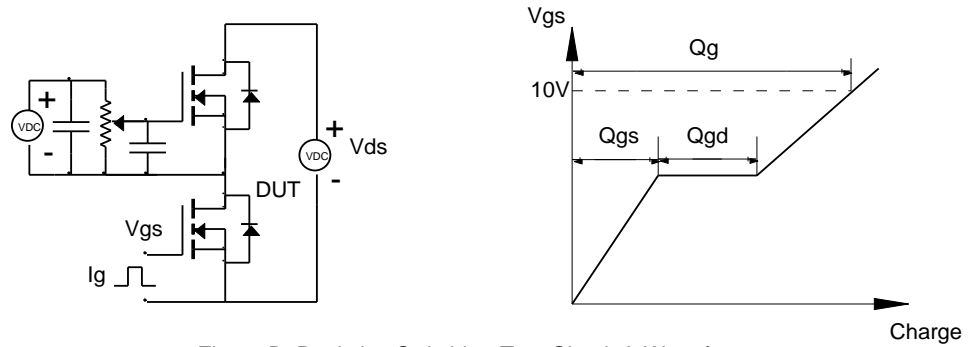


Figure B: Resistive Switching Test Circuit & Waveforms

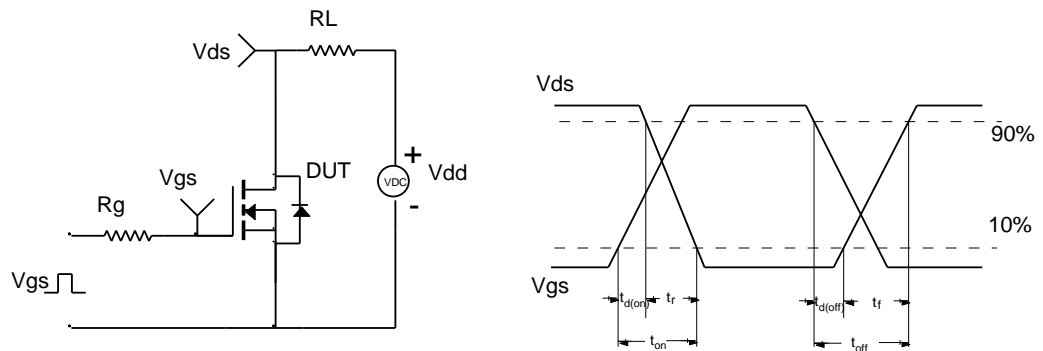


Figure C: Unclamped Inductive Switching (UIS) Test Circuit & Waveforms

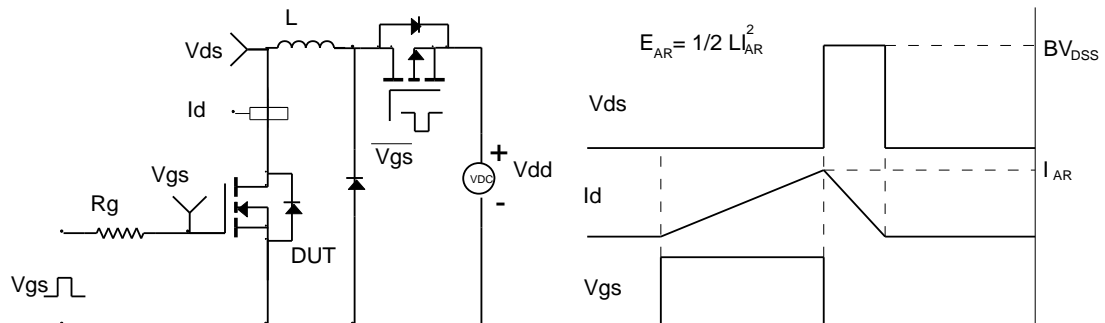
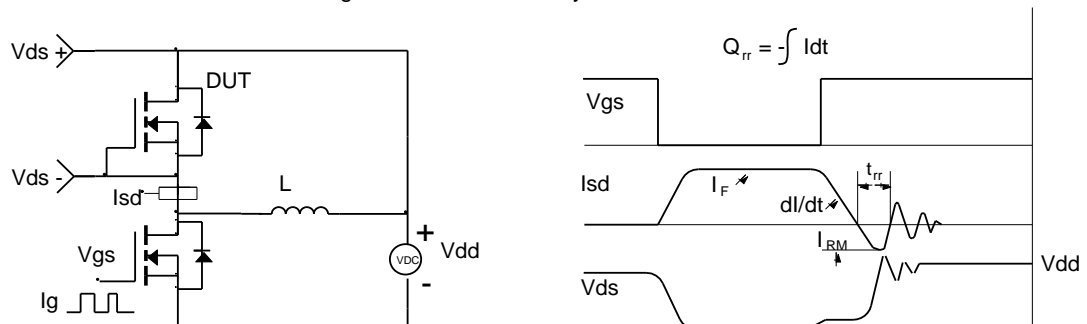


Figure D: Diode Recovery Test Circuit & Waveforms



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